

Ethylene Glycol
CMOS



Material No.: 9346-05
Batch No.: 0000020005
Manufactured Date: 2012/10/01
Retest Date: 2017/09/30

Certificate of Analysis

Test	Specification	Result
Assay (HOCH ₂ CH ₂ OH) (by GC)	>= 99.0 %	99.9
Color (APHA)	<= 10	5
Acidity (µeq/g)	<= 0.8	0.4
Acidity (as CH ₃ COOH)(by wt)	<= 0.01 %	< 0.01
Residue after Ignition	<= 0.005 %	< 0.001
Water (H ₂ O)(by Karl Fischer titrn)	<= 0.2 %	< 0.1
Chloride (Cl)	<= 1 ppm	< 1
Phosphate (PO ₄)	<= 2 ppm	< 2
Sulfate (SO ₄)	<= 2 ppm	< 2
Arsenic and Antimony (as As)	<= 0.100 ppm	< 0.100
Trace Impurities – Iron (Fe)	<= 0.2 ppm	0.0
Trace Impurities – Aluminum (Al)	<= 100.0 ppb	5.0
Trace Impurities – Barium (Ba)	<= 100.0 ppb	< 1.0
Trace Impurities – Boron (B)	<= 50.0 ppb	< 5.0
Trace Impurities – Calcium (Ca)	<= 300.0 ppb	7.6
Trace Impurities – Chromium (Cr)	<= 50.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities – Gold (Au)	<= 50.0 ppb	< 5.0
Trace Impurities – Lead (Pb)	<= 200.0 ppb	< 10.0
Trace Impurities – Lithium (Li)	<= 100.0 ppb	< 1.0
Trace Impurities – Magnesium (Mg)	<= 100.0 ppb	2.3
Trace Impurities – Manganese (Mn)	<= 100.0 ppb	< 1.0
Trace Impurities – Nickel (Ni)	<= 100.0 ppb	< 5.0
Trace Impurities – Potassium (K)	<= 300.0 ppb	< 10.0

Test	Specification	Result
Trace Impurities - Sodium (Na)	<= 300.0 ppb	5.0
Trace Impurities - Tin (Sn)	<= 100.0 ppb	< 10.0
Trace Impurities - Titanium (Ti)	<= 100.0 ppb	< 1.0
Trace Impurities - Zinc (Zn)	<= 400.0 ppb	8.2
Particle Count - 0.5 µm and greater	<= 200 par/ml	12
Particle Count - 1.0 µm and greater	<= 10 par/ml	6

For Microelectronic Use

Country of Origin: US
Packaging Site: Paris Mfg Ctr & DC

ISO Phillipsburg, NJ 9001.2008, 14001.2004
Paris, KY 9001.2008
Mexico city, Mexico 9001.2008
Deventer, The Netherlands 9001.2008, 14001.2004
Selangor, Malaysia 9001.2008
Panoli, India 9001.2008
Gliwice, Poland 9001.2008, 17025.2005

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